

Investigations of the diagnosability of digital networks with BIST

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan 10th IEEE Latin American Test Workshop : 2-5 March 2009, Brazil 2009 / [6] p. : ill

Turning JTAG inside out for fast extended test access

Devadze, Sergei; Jutman, Artur; Aleksejev, Igor; Ubar, Raimund-Johannes 10th IEEE Latin American Test Workshop : 2-5 March 2009, Brazil 2009 / [6] p. : ill <https://ieeexplore.ieee.org/document/4813799>